Datacolor ELREPHO

Performance, Trusted by the Paper Industry

Datacolor ELREPHO, a trusted spectrophotometer for the paper industry, suitable for the reference laboratory or production control of color, brightness, opacity, diffuse reflectance factors, yellowness, and whiteness of pulp, paper and chemicals. It uses a diffuse/0 optical geometry and automated, adjustable, ISO 2469 compliant UV filter.

Designed for: Laboratory and quality control of pulp, paper and paper components.

Designed for the Paper Industry

Datacolor ELREPHO is a high performance spectrophotometer made for the paper industry, perfect for the reference laboratory or production control of color, brightness, opacity, yellowness and whiteness measurements of pulp, paper and chemicals used in paper and coating manufacturing. The dual beam spectrophotometer with diffuse/0 optical geometry and an adjustable UV filter conforms to ISO 2469.

Easy Application & Efficient Workflow

Simple operation of sample presentation and alignment is facilitated by the vertical configuration and through-the-sphere sample viewer, enabling faster measurement throughput. Three aperture plates are included with the instrument. SAV and USAV plates enable accurate measurement of small and very small areas of a sample, while the XLAV plate is recommended for irregular and textured sample averaging.

Backward Compatibility

Being compatible with the preceding Elrepho 3000 series, it achieves very close agreement among all instruments in your supply chain. Along with the instrument, the Datacolor SP 2000 spectrophotometer is included: a durable, pulsed xenon light source to approximate D65, an automated zoom lens, and adjustable, automated UV cut-off filters for three wavelengths to control the UV component from the light source.

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Datacolor ELREPHO uses serial or USB connections to interface with the Datacolor TOOLS quality control software. It supports measurement procedures for the paper industry as defined by ISO, DIN, SCAN and TAPPI Standards.

What you get:

- Six-foot power cable
- Serial cable with connectors on either end
- USB cable
- Black trap
- White tile
- Green tile

Aperture Plates:

- Extra-Large Area View (XLAV)
- Small Area View (SAV)
- Ultra Small Area View (USAV)

Feature	Elrepho
Instrument Type	dual-beam spectrophotometer
Measurement Geometry	diffuse illumination and 0° viewing
Illumination Source	pulsed xenon filtered to approximate D65
Sphere Diameter	152 mm / 6.0 in
Spectral Analyzer	SP2000 analyzer with dual 256 diode array and high-resolution holographic grating
Wavelength Range	360 nm to 700 nm
Reporting Interval	10 nm
Effective Bandwidth	10 nm
Wavelength Resolution	2 nm
Photometric Range:	0 to 200%
Photometric Resolution	0.003%
Black Trap	high performance
20 Read Repeatability On The White Tile Using Dual Flash (CIELAB)	0.02 (max)
Inter-instrument Agreement1 (CIELAB)	0.4 (maximum), 0.2 (average)
Lens	3 position auto zoom
XLAV Aperture plate	34 mm illuminated and 30 mm measured
SAV Aperture plate	9 mm illuminated and 5 mm measured
USAV Aperture plate	6.5 mm illuminated and 2.5 mm measured
Automatic UV Control	automatic UV calibration for the measurement of fluorescent specimens with UV cutoff filters at 395 nm, 420 nm and 460 nm
Vertical Mount	includes peephole sample viewer and pedestal sample holder
Height	640 mm / 25 3/16 in
Width	312 mm / 12 5/16 in
Depth	371 mm / 14 5/8 in
Weight	19.05 kg / 42 lb
Power Requirements	85 to 264 VAC, 47 to 63 Hz, 80 VA peak, 35 VA typical
Absolute Operating Range	5° to 40° C, 5% to 85% non-condensing relative humidity
Interface	RS-232 9600/19200 baud

For more information, please visit www.datacolor.com/